



## Short description

The P302 L-EFT pulse-voltage generator is used for the conductive coupling of disturbance pulses into test ICs. During tests according to the standards IEC 61000-4-2 / ICE 61000-4-4 the P302 simuates the reduced disturbance pulses that have reached the IC. These disturbance-voltage pulses created during the test can result from electric-field coupling.

When an electrical disturbance field couples into the traces of a test IC, the disturbance voltage of the connected impedances will drop. This voltage drop occurs at the IC pins can lead to functional interferences. This coupling mechanism can be simulated by a high-impedance pulse-voltage source, such as the P302 generator ( $\approx 150 \Omega$ ). The pulse voltage is adjustable within the range of ± (5 - 500) V. The L-EFT generator is operated with the BPS 202 and the BPS 202-Client software. To test ICs at the measuring station the ICE1 test environment is required. For automated testing the ICE1 as well as the ICT1 IC tester is required. Additional equipment may be needed for other measurements (Oscilloscope, PC).

## **Technical parameters**

Internal resistance	≈ 150 Ω
Coupling capacity	20 pF
Pulse parameter	
Shape	1.5 / 20 ns
Frequency	0.1 Hz - 10 kHz
Voltage	± (5 - 500) V
Inductance	50 nH
Sizes (L x W x H)	(78 x 35 x 31) mm